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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Obsolete
Core Processor	R8C
Core Size	16-Bit
Speed	20MHz
Connectivity	I <sup>2</sup> C, LINbus, SIO, SSU, UART/USART
Peripherals	LED, POR, Voltage Detect, WDT
Number of I/O	25
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	1K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 5.5V
Data Converters	A/D 12x10b
Oscillator Type	Internal
Operating Temperature	-20°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	32-LQFP (7x7)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f21264syfp-x6">https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f21264syfp-x6</a>

## 1.4 Product Information

Table 1.3 lists the Product Information for R8C/26 Group and Table 1.4 lists the Product Information for R8C/27 Group.

**Table 1.3 Product Information for R8C/26 Group**

**Current of Sep. 2008**

Part No.	ROM Capacity	RAM Capacity	Package Type	Remarks		
R5F21262SNFP	8 Kbytes	512 bytes	PLQP0032GB-A	N version		
R5F21264SNFP	16 Kbytes	1 Kbyte	PLQP0032GB-A			
R5F21265SNFP	24 Kbytes	1.5 Kbytes	PLQP0032GB-A			
R5F21266SNFP	32 Kbytes	1.5 Kbytes	PLQP0032GB-A			
R5F21262SDFP	8 Kbytes	512 bytes	PLQP0032GB-A	D version		
R5F21264SDFP	16 Kbytes	1 Kbyte	PLQP0032GB-A			
R5F21265SDFP	24 Kbytes	1.5 Kbytes	PLQP0032GB-A			
R5F21266SDFP	32 Kbytes	1.5 Kbytes	PLQP0032GB-A			
R5F21264JFP	16 Kbytes	1 Kbyte	PLQP0032GB-A	J version		
R5F21266JFP	32 Kbytes	1.5 Kbytes	PLQP0032GB-A			
R5F21264KFP	16 Kbytes	1 Kbyte	PLQP0032GB-A	K version		
R5F21266KFP	32 Kbytes	1.5 Kbytes	PLQP0032GB-A			
R5F21262SNXXXFP	8 Kbytes	512 bytes	PLQP0032GB-A	N version	Factory programming product <sup>(1)</sup>	
R5F21264SNXXXFP	16 Kbytes	1 Kbyte	PLQP0032GB-A			
R5F21265SNXXXFP	24 Kbytes	1.5 Kbytes	PLQP0032GB-A			
R5F21266SNXXXFP	32 Kbytes	1.5 Kbytes	PLQP0032GB-A			
R5F21262SDXXXFP	8 Kbytes	512 bytes	PLQP0032GB-A	D version		
R5F21264SDXXXFP	16 Kbytes	1 Kbyte	PLQP0032GB-A			
R5F21265SDXXXFP	24 Kbytes	1.5 Kbytes	PLQP0032GB-A			
R5F21266SDXXXFP	32 Kbytes	1.5 Kbytes	PLQP0032GB-A			
R5F21264JXXXFP	16 Kbytes	1 Kbyte	PLQP0032GB-A	J version		
R5F21266JXXXFP	32 Kbytes	1.5 Kbytes	PLQP0032GB-A			
R5F21264KXXXFP	16 Kbytes	1 Kbyte	PLQP0032GB-A	K version		
R5F21266KXXXFP	32 Kbytes	1.5 Kbytes	PLQP0032GB-A			

NOTE:

1. The user ROM is programmed before shipment.

### 3. Memory

#### 3.1 R8C/26 Group

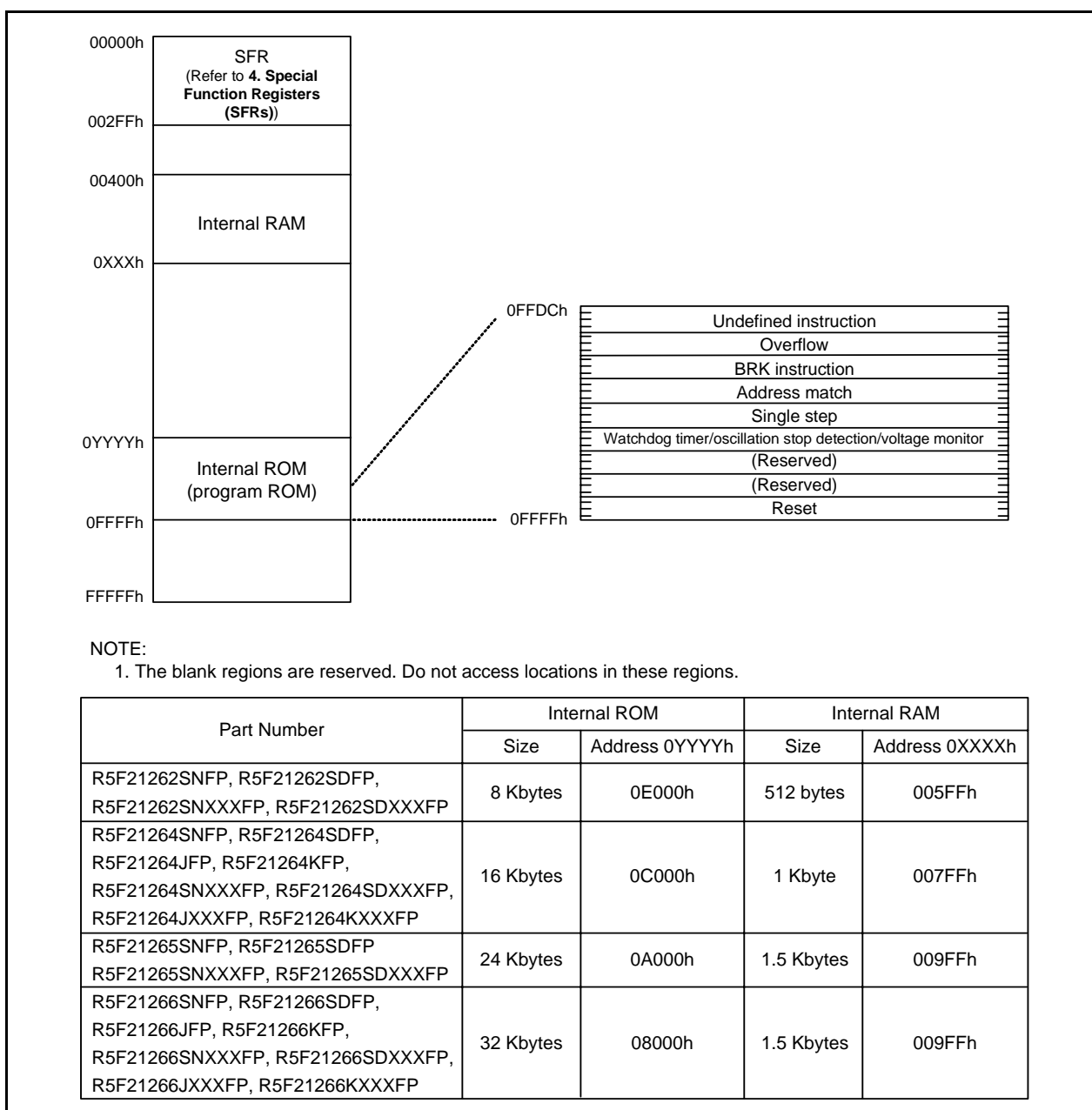
Figure 3.1 is a Memory Map of R8C/26 Group. The R8C/26 group has 1 Mbyte of address space from addresses 00000h to FFFFFh.

The internal ROM is allocated lower addresses, beginning with address 0FFFFh. For example, a 16-Kbyte internal ROM area is allocated addresses 0C000h to 0FFFFh.

The fixed interrupt vector table is allocated addresses 0FFDCh to 0FFFFh. They store the starting address of each interrupt routine.

The internal RAM is allocated higher addresses beginning with address 00400h. For example, a 1-Kbyte internal RAM area is allocated addresses 00400h to 007FFh. The internal RAM is used not only for storing data but also for calling subroutines and as stacks when interrupt requests are acknowledged.

Special function registers (SFRs) are allocated addresses 00000h to 002FFh. The peripheral function control registers are allocated here. All addresses within the SFR, which have nothing allocated are reserved for future use and cannot be accessed by users.



**Figure 3.1 Memory Map of R8C/26 Group**

## 4. Special Function Registers (SFRs)

An SFR (special function register) is a control register for a peripheral function. Tables 4.1 to 4.7 list the special function registers.

**Table 4.1 SFR Information (1)(1)**

Address	Register	Symbol	After reset
0000h			
0001h			
0002h			
0003h			
0004h	Processor Mode Register 0	PM0	00h
0005h	Processor Mode Register 1	PM1	00h
0006h	System Clock Control Register 0	CM0	01101000b
0007h	System Clock Control Register 1	CM1	00100000b
0008h			
0009h			
000Ah	Protect Register	PRCR	00h
000Bh			
000Ch	Oscillation Stop Detection Register	OCD	00000100b
000Dh	Watchdog Timer Reset Register	WDTR	XXh
000Eh	Watchdog Timer Start Register	WDTS	XXh
000Fh	Watchdog Timer Control Register	WDC	00X11111b
0010h	Address Match Interrupt Register 0	RMAD0	00h
0011h			00h
0012h			00h
0013h	Address Match Interrupt Enable Register	AIER	00h
0014h	Address Match Interrupt Register 1	RMAD1	00h
0015h			00h
0016h			00h
0017h			00h
0018h			
0019h			
001Ah			
001Bh			
001Ch	Count Source Protection Mode Register	CSPR	00h 10000000b <sup>(2)</sup>
001Dh			
001Eh			
001Fh			
0020h			
0021h			
0022h			
0023h	High-Speed On-Chip Oscillator Control Register 0	FRA0	00h
0024h	High-Speed On-Chip Oscillator Control Register 1	FRA1	When shipping
0025h	High-Speed On-Chip Oscillator Control Register 2	FRA2	00h
0026h			
0027h			
0028h	Clock Prescaler Reset Flag	CPSRF	00h
0029h	High-Speed On-Chip Oscillator Control Register 4 <sup>(3)</sup>	FRA4	When shipping
002Ah			
002Bh	High-Speed On-Chip Oscillator Control Register 6 <sup>(3)</sup>	FRA6	When shipping
002Ch	High-Speed On-Chip Oscillator Control Register 7 <sup>(3)</sup>	FRA7	When shipping
002Dh			
002Eh			
002Fh			

X: Undefined

**NOTES:**

1. The blank regions are reserved. Do not access locations in these regions.
2. The CSPROINI bit in the OFS register is set to 0.
3. In J, K version these regions are reserved. Do not access locations in these regions.

**Table 5.5 Flash Memory (Data flash Block A, Block B) Electrical Characteristics<sup>(4)</sup>**

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
—	Program/erase endurance <sup>(2)</sup>		10,000 <sup>(3)</sup>	—	—	times
—	Byte program time (program/erase endurance ≤ 1,000 times)		—	50	400	μs
—	Byte program time (program/erase endurance > 1,000 times)		—	65	—	μs
—	Block erase time (program/erase endurance ≤ 1,000 times)		—	0.2	9	s
—	Block erase time (program/erase endurance > 1,000 times)		—	0.3	—	s
t <sub>d</sub> (SR-SUS)	Time delay from suspend request until suspend		—	—	97 + CPU clock × 6 cycles	μs
—	Interval from erase start/restart until following suspend request		650	—	—	μs
—	Interval from program start/restart until following suspend request		0	—	—	ns
—	Time from suspend until program/erase restart		—	—	3 + CPU clock × 4 cycles	μs
—	Program, erase voltage		2.7	—	5.5	V
—	Read voltage		2.2	—	5.5	V
—	Program, erase temperature		-20 <sup>(8)</sup>	—	85	°C
—	Data hold time <sup>(9)</sup>	Ambient temperature = 55°C	20	—	—	year

**NOTES:**

1. V<sub>CC</sub> = 2.7 to 5.5 V at T<sub>opr</sub> = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.
2. Definition of programming/erasure endurance  
The programming and erasure endurance is defined on a per-block basis.  
If the programming and erasure endurance is n (n = 10,000), each block can be erased n times. For example, if 1,024 1-byte writes are performed to different addresses in block A, a 1 Kbyte block, and then the block is erased, the programming/erasure endurance still stands at one.  
However, the same address must not be programmed more than once per erase operation (overwriting prohibited).
3. Endurance to guarantee all electrical characteristics after program and erase. (1 to Min. value can be guaranteed).
4. Standard of block A and block B when program and erase endurance exceeds 1,000 times. Byte program time to 1,000 times is the same as that in program ROM.
5. In a system that executes multiple programming operations, the actual erasure count can be reduced by writing to sequential addresses in turn so that as much of the block as possible is used up before performing an erase operation. For example, when programming groups of 16 bytes, the effective number of rewrites can be minimized by programming up to 128 groups before erasing them all in one operation. In addition, averaging the erasure endurance between blocks A and B can further reduce the actual erasure endurance. It is also advisable to retain data on the erasure endurance of each block and limit the number of erase operations to a certain number.
6. If an error occurs during block erase, attempt to execute the clear status register command, then execute the block erase command at least three times until the erase error does not occur.
7. Customers desiring program/erase failure rate information should contact their Renesas technical support representative.
8. -40°C for D version.
9. The data hold time includes time that the power supply is off or the clock is not supplied.

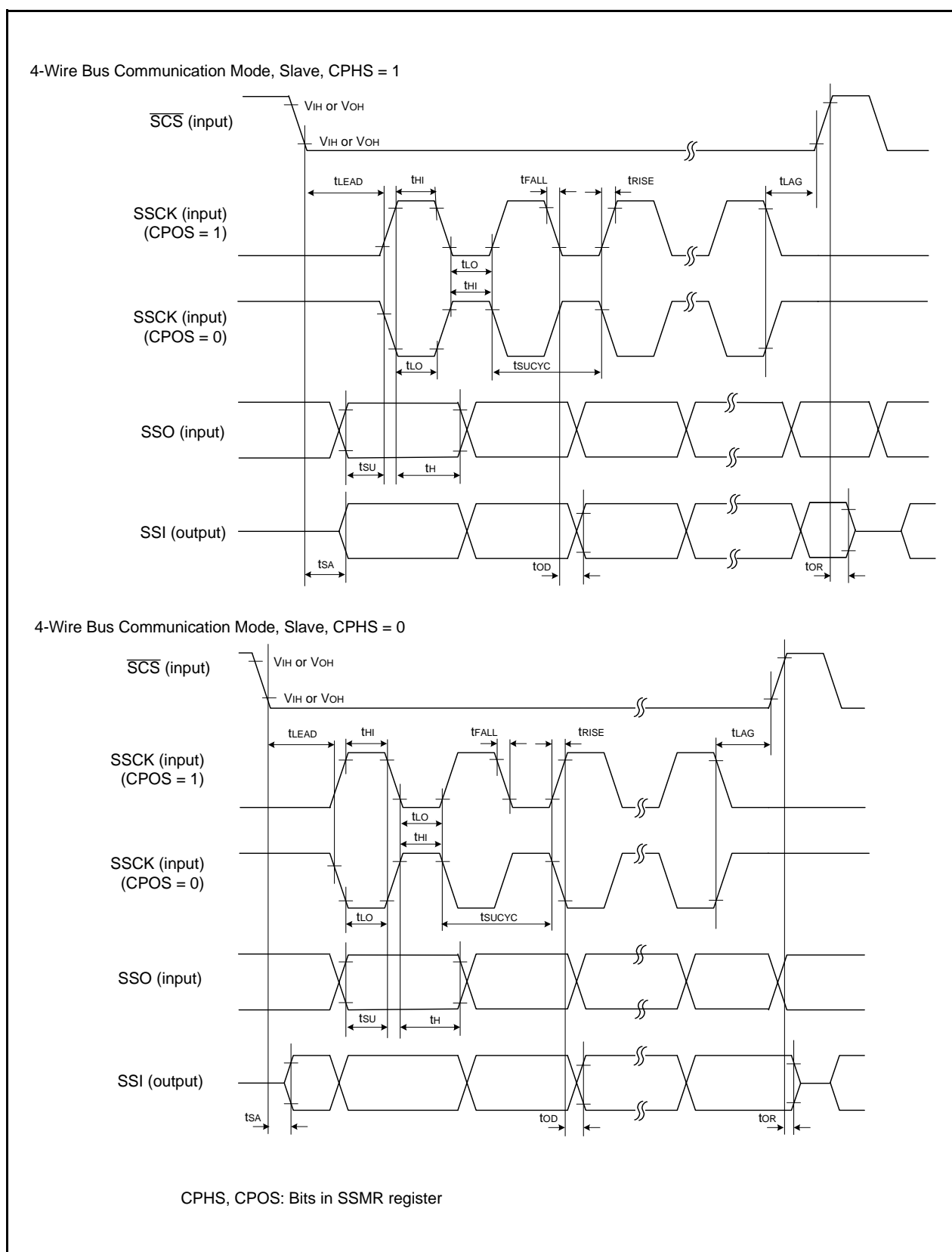
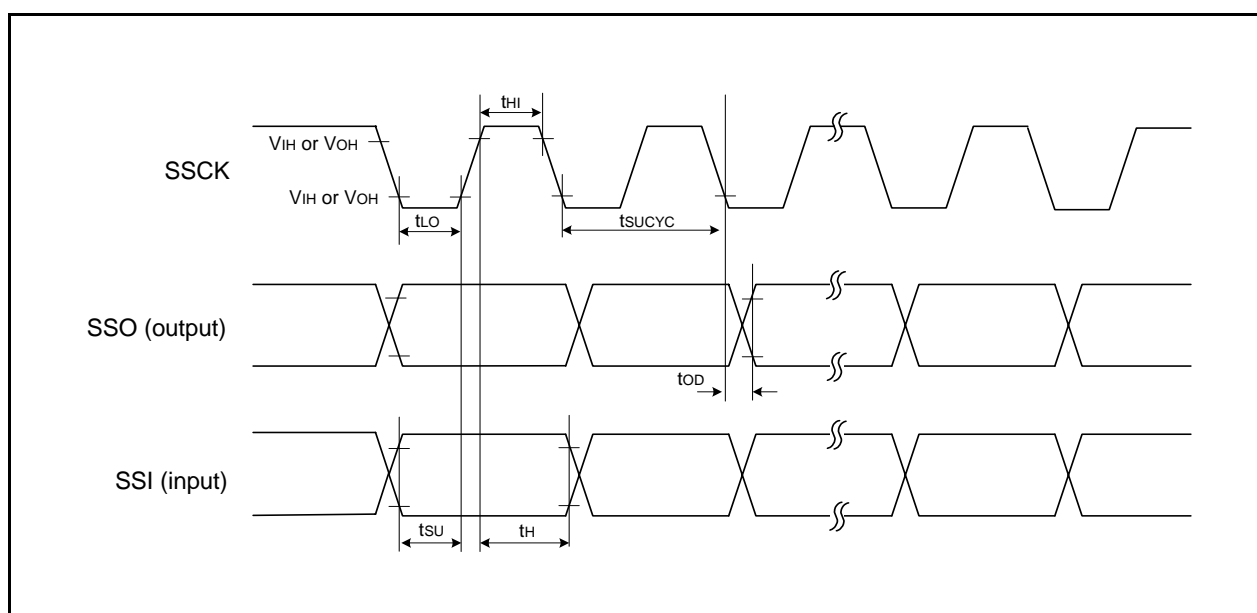


Figure 5.5 I/O Timing of Clock Synchronous Serial I/O with Chip Select (Slave)

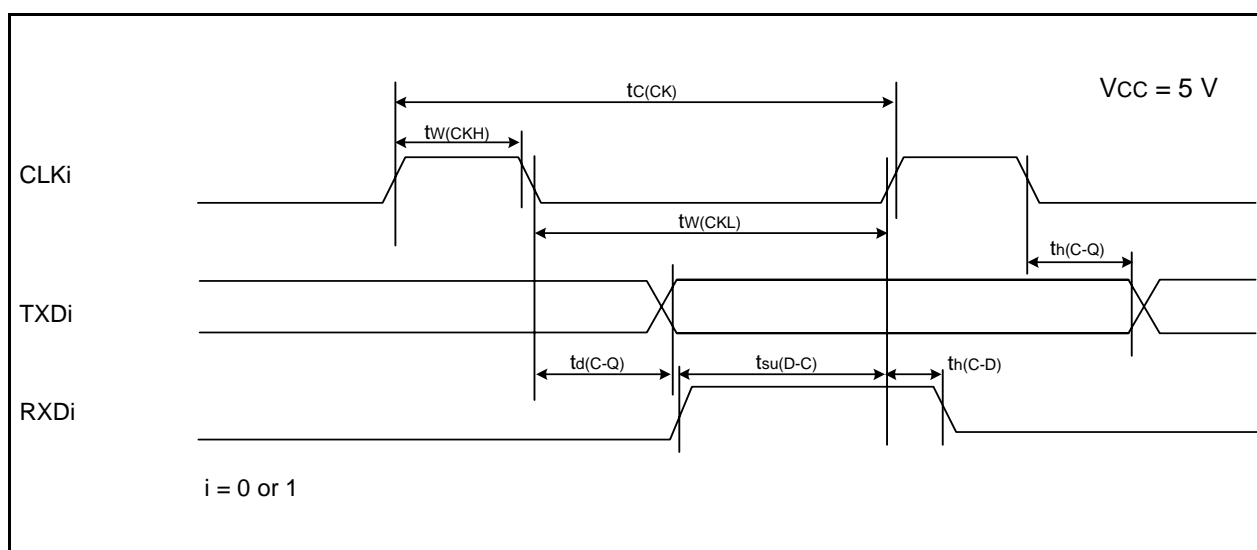


**Figure 5.6 I/O Timing of Clock Synchronous Serial I/O with Chip Select (Clock Synchronous Communication Mode)**

**Table 5.20 Serial Interface**

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(CK)}$	CLKi input cycle time	200	—	ns
$t_{w(CKH)}$	CLKi input "H" width	100	—	ns
$t_{w(CKL)}$	CLKi input "L" width	100	—	ns
$t_{d(C-Q)}$	TXDi output delay time	—	50	ns
$t_{h(C-Q)}$	TXDi hold time	0	—	ns
$t_{su(D-C)}$	RXDi input setup time	50	—	ns
$t_{h(C-D)}$	RXDi input hold time	90	—	ns

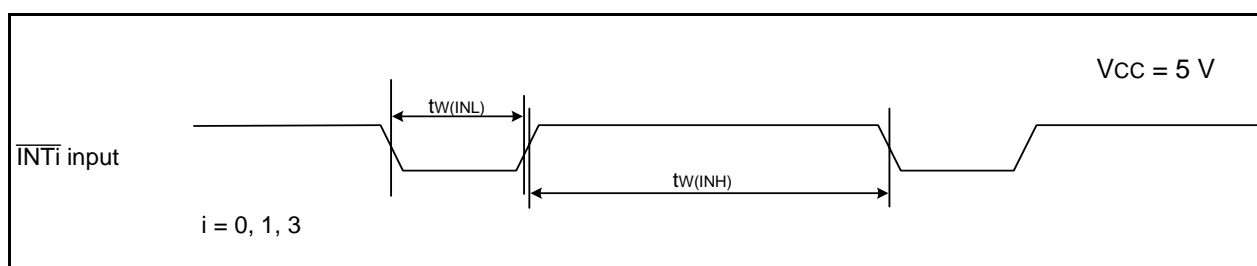
i = 0 or 1

**Figure 5.10 Serial Interface Timing Diagram when Vcc = 5 V****Table 5.21 External Interrupt  $\overline{INTi}$  (i = 0, 1, 3) Input**

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{w(INH)}$	$\overline{INTi}$ input "H" width	250 <sup>(1)</sup>	—	ns
$t_{w(INL)}$	$\overline{INTi}$ input "L" width	250 <sup>(2)</sup>	—	ns

**NOTES:**

1. When selecting the digital filter by the  $\overline{INTi}$  input filter select bit, use an  $\overline{INTi}$  input HIGH width of either (1/digital filter clock frequency × 3) or the minimum value of standard, whichever is greater.
2. When selecting the digital filter by the  $\overline{INTi}$  input filter select bit, use an  $\overline{INTi}$  input LOW width of either (1/digital filter clock frequency × 3) or the minimum value of standard, whichever is greater.

**Figure 5.11 External Interrupt  $\overline{INTi}$  Input Timing Diagram when Vcc = 5 V**



**Table 5.22 Electrical Characteristics (3) [V<sub>CC</sub> = 3 V]**

Symbol	Parameter		Condition		Standard			Unit
					Min.	Typ.	Max.	
V <sub>OH</sub>	Output "H" voltage	Except P1_0 to P1_7, XOUT	I <sub>OH</sub> = -1 mA		V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
		P1_0 to P1_7	Drive capacity HIGH	I <sub>OH</sub> = -5 mA	V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
			Drive capacity LOW	I <sub>OH</sub> = -1 mA	V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
		XOUT	Drive capacity HIGH	I <sub>OH</sub> = -0.1 mA	V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
			Drive capacity LOW	I <sub>OH</sub> = -50 μA	V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
V <sub>OL</sub>	Output "L" voltage	Except P1_0 to P1_7, XOUT	I <sub>OL</sub> = 1 mA		—	—	0.5	V
		P1_0 to P1_7	Drive capacity HIGH	I <sub>OL</sub> = 5 mA	—	—	0.5	V
			Drive capacity LOW	I <sub>OL</sub> = 1 mA	—	—	0.5	V
		XOUT	Drive capacity HIGH	I <sub>OL</sub> = 0.1 mA	—	—	0.5	V
			Drive capacity LOW	I <sub>OL</sub> = 50 μA	—	—	0.5	V
V <sub>T+</sub> -V <sub>T-</sub>	Hysteresis	$\overline{\text{INT0}}, \overline{\text{INT1}}, \overline{\text{INT3}}, \overline{\text{KI0}}, \overline{\text{KI1}}, \overline{\text{KI2}}, \overline{\text{KI3}}, \overline{\text{TRAIO}}, \overline{\text{RXD0}}, \overline{\text{RXD1}}, \overline{\text{CLK0}}, \overline{\text{CLK1}}, \overline{\text{SSI}}, \overline{\text{SCL}}, \overline{\text{SDA}}, \overline{\text{SSO}}$			0.1	0.3	—	V
		$\overline{\text{RESET}}$			0.1	0.4	—	V
I <sub>IH</sub>	Input "H" current		V <sub>I</sub> = 3 V, V <sub>CC</sub> = 3 V		—	—	4.0	μA
I <sub>IL</sub>	Input "L" current		V <sub>I</sub> = 0 V, V <sub>CC</sub> = 3 V		—	—	-4.0	μA
R <sub>PULLUP</sub>	Pull-up resistance		V <sub>I</sub> = 0 V, V <sub>CC</sub> = 3 V		66	160	500	kΩ
R <sub>FXIN</sub>	Feedback resistance	XIN			—	3.0	—	MΩ
R <sub>FXCIN</sub>	Feedback resistance	XCIN			—	18	—	MΩ
V <sub>RAM</sub>	RAM hold voltage		During stop mode		1.8	—	—	V

## NOTE:

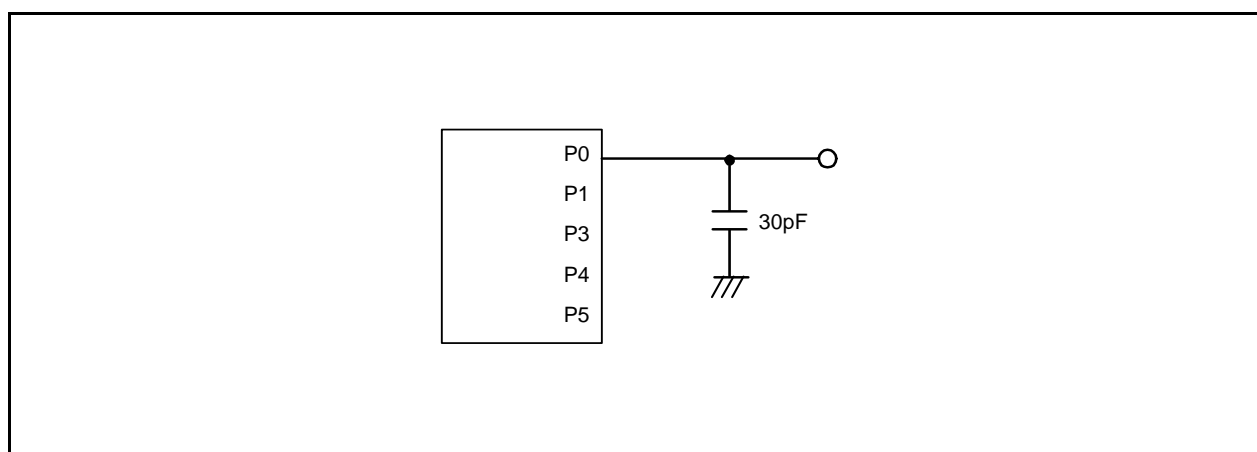
- V<sub>CC</sub> = 2.7 to 3.3 V at T<sub>opr</sub> = -20 to 85°C (N version) / -40 to 85°C (D version), f(XIN) = 10 MHz, unless otherwise specified.

**Table 5.36 A/D Converter Characteristics**

Symbol	Parameter		Conditions	Standard			Unit
				Min.	Typ.	Max.	
—	Resolution		$V_{ref} = AV_{CC}$	—	—	10	Bits
—	Absolute accuracy	10-bit mode	$\phi_{AD} = 10 \text{ MHz}$ , $V_{ref} = AV_{CC} = 5.0 \text{ V}$	—	—	$\pm 3$	LSB
		8-bit mode	$\phi_{AD} = 10 \text{ MHz}$ , $V_{ref} = AV_{CC} = 5.0 \text{ V}$	—	—	$\pm 2$	LSB
		10-bit mode	$\phi_{AD} = 10 \text{ MHz}$ , $V_{ref} = AV_{CC} = 3.3 \text{ V}$	—	—	$\pm 5$	LSB
		8-bit mode	$\phi_{AD} = 10 \text{ MHz}$ , $V_{ref} = AV_{CC} = 3.3 \text{ V}$	—	—	$\pm 2$	LSB
$R_{ladder}$	Resistor ladder		$V_{ref} = AV_{CC}$	10	—	40	$k\Omega$
$t_{conv}$	Conversion time	10-bit mode	$\phi_{AD} = 10 \text{ MHz}$ , $V_{ref} = AV_{CC} = 5.0 \text{ V}$	3.3	—	—	$\mu\text{s}$
		8-bit mode	$\phi_{AD} = 10 \text{ MHz}$ , $V_{ref} = AV_{CC} = 5.0 \text{ V}$	2.8	—	—	$\mu\text{s}$
$V_{ref}$	Reference voltage			2.7	—	$AV_{CC}$	V
$V_{IA}$	Analog input voltage <sup>(2)</sup>			0	—	$AV_{CC}$	V
—	A/D operating clock frequency	Without sample and hold		0.25	—	10	MHz
		With sample and hold		1	—	10	MHz

## NOTES:

1.  $AV_{CC} = 2.7$  to  $5.5 \text{ V}$  at  $T_{opr} = -40$  to  $85^\circ\text{C}$  (J version) /  $-40$  to  $125^\circ\text{C}$  (K version), unless otherwise specified.
2. When the analog input voltage is over the reference voltage, the A/D conversion result will be 3FFh in 10-bit mode and FFh in 8-bit mode.

**Figure 5.20 Ports P0, P1, and P3 to P5 Timing Measurement Circuit**

**Table 5.37 Flash Memory (Program ROM) Electrical Characteristics**

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
—	Program/erase endurance <sup>(2)</sup>	R8C/26 Group	100 <sup>(3)</sup>	—	—	times
		R8C/27 Group	1,000 <sup>(3)</sup>	—	—	times
—	Byte program time		—	50	400	μs
—	Block erase time		—	0.4	9	s
t <sub>d</sub> (SR-SUS)	Time delay from suspend request until suspend		—	—	97 + CPU clock × 6 cycles	μs
—	Interval from erase start/restart until following suspend request		650	—	—	μs
—	Interval from program start/restart until following suspend request		0	—	—	ns
—	Time from suspend until program/erase restart		—	—	3 + CPU clock × 4 cycles	μs
—	Program, erase voltage		2.7	—	5.5	V
—	Read voltage		2.7	—	5.5	V
—	Program, erase temperature		0	—	60	°C
—	Data hold time <sup>(7)</sup>	Ambient temperature = 55°C	20	—	—	year

**NOTES:**

1. V<sub>CC</sub> = 2.7 to 5.5 V at T<sub>opr</sub> = 0 to 60°C, unless otherwise specified.
2. Definition of programming/erasure endurance  
The programming and erasure endurance is defined on a per-block basis.  
If the programming and erasure endurance is n (n = 100 or 1,000), each block can be erased n times. For example, if 1,024 1-byte writes are performed to different addresses in block A, a 1 Kbyte block, and then the block is erased, the programming/erasure endurance still stands at one.  
However, the same address must not be programmed more than once per erase operation (overwriting prohibited).
3. Endurance to guarantee all electrical characteristics after program and erase. (1 to Min. value can be guaranteed).
4. In a system that executes multiple programming operations, the actual erasure count can be reduced by writing to sequential addresses in turn so that as much of the block as possible is used up before performing an erase operation. For example, when programming groups of 16 bytes, the effective number of rewrites can be minimized by programming up to 128 groups before erasing them all in one operation. It is also advisable to retain data on the erasure endurance of each block and limit the number of erase operations to a certain number.
5. If an error occurs during block erase, attempt to execute the clear status register command, then execute the block erase command at least three times until the erase error does not occur.
6. Customers desiring program/erase failure rate information should contact their Renesas technical support representative.
7. The data hold time includes time that the power supply is off or the clock is not supplied.

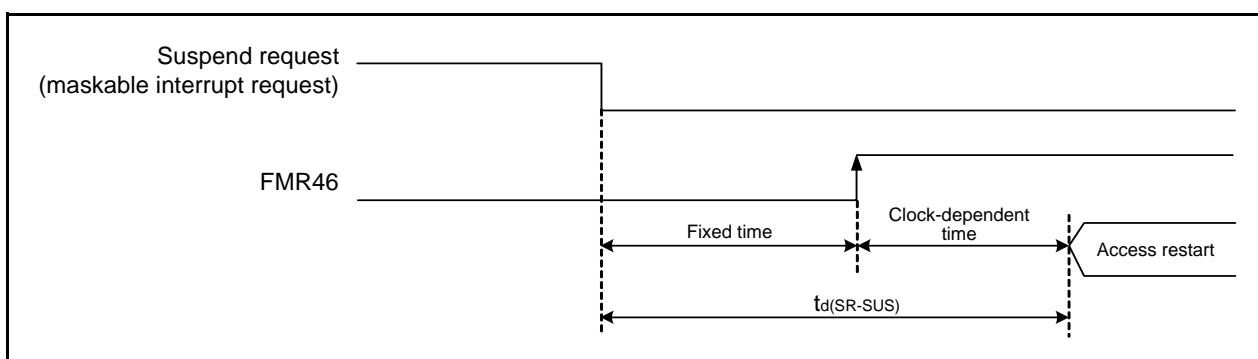


Figure 5.21 Time delay until Suspend

Table 5.39 Voltage Detection 1 Circuit Electrical Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
V <sub>det1</sub>	Voltage detection level <sup>(2, 4)</sup>		2.70	2.85	3.0	V
t <sub>d</sub> (V <sub>det1</sub> -A)	Voltage monitor 1 reset generation time <sup>(5)</sup>		—	40	200	μs
—	Voltage detection circuit self power consumption	VCA26 = 1, V <sub>CC</sub> = 5.0 V	—	0.6	—	μA
t <sub>d</sub> (E-A)	Waiting time until voltage detection circuit operation starts <sup>(3)</sup>		—	—	100	μs
V <sub>ccmin</sub>	MCU operating voltage minimum value		2.70	—	—	V

## NOTES:

1. The measurement condition is V<sub>CC</sub> = 2.7 to 5.5 V and T<sub>opr</sub> = -40 to 85°C (J version) / -40 to 125°C (K version).
2. Hold V<sub>det2</sub> > V<sub>det1</sub>.
3. Necessary time until the voltage detection circuit operates when setting to 1 again after setting the VCA26 bit in the VCA2 register to 0.
4. This parameter shows the voltage detection level when the power supply drops.  
The voltage detection level when the power supply rises is higher than the voltage detection level when the power supply drops by approximately 0.1 V.
5. Time until the voltage monitor 1 reset is generated after the voltage passes V<sub>det1</sub> when V<sub>CC</sub> falls. When using the digital filter, its sampling time is added to t<sub>d</sub>(V<sub>det1</sub>-A). When using the voltage monitor 1 reset, maintain this time until V<sub>CC</sub> = 2.0 V after the voltage passes V<sub>det1</sub> when the power supply falls.

Table 5.40 Voltage Detection 2 Circuit Electrical Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
V <sub>det2</sub>	Voltage detection level <sup>(2)</sup>		3.3	3.6	3.9	V
t <sub>d</sub> (V <sub>det2</sub> -A)	Voltage monitor 2 reset/interrupt request generation time <sup>(3, 5)</sup>		—	40	200	μs
—	Voltage detection circuit self power consumption	VCA27 = 1, V <sub>CC</sub> = 5.0 V	—	0.6	—	μA
t <sub>d</sub> (E-A)	Waiting time until voltage detection circuit operation starts <sup>(4)</sup>		—	—	100	μs

## NOTES:

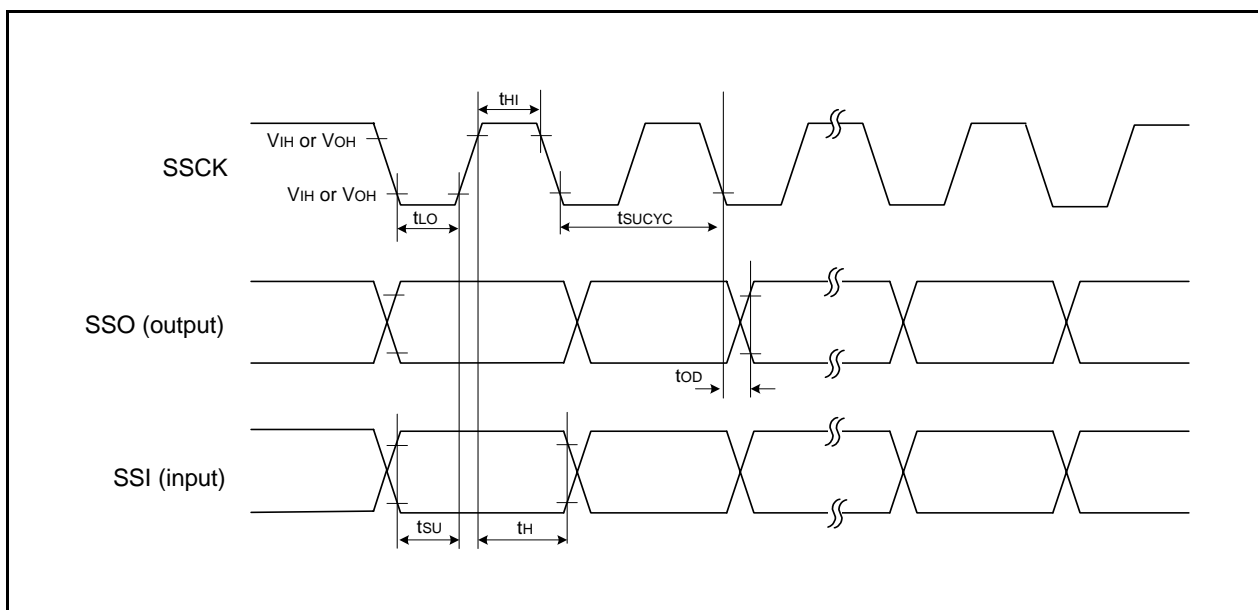
1. The measurement condition is V<sub>CC</sub> = 2.7 to 5.5 V and T<sub>opr</sub> = -40 to 85°C (J version) / -40 to 125°C (K version).
2. Hold V<sub>det2</sub> > V<sub>det1</sub>.
3. Time until the voltage monitor 2 reset/interrupt request is generated after the voltage passes V<sub>det2</sub>.
4. Necessary time until the voltage detection circuit operates after setting to 1 again after setting the VCA27 bit in the VCA2 register to 0.
5. When using the digital filter, its sampling time is added to t<sub>d</sub>(V<sub>det2</sub>-A). When using the voltage monitor 2 reset, maintain this time until V<sub>CC</sub> = 2.0 V after the voltage passes V<sub>det2</sub> when the power supply falls.

**Table 5.45 Timing Requirements of Clock Synchronous Serial I/O with Chip Select<sup>(1)</sup>**

Symbol	Parameter		Conditions	Standard			Unit
				Min.	Typ.	Max.	
tsucyc	SSCK clock cycle time			4	—	—	tcyc <sup>(2)</sup>
tHI	SSCK clock "H" width			0.4	—	0.6	tsucyc
tLO	SSCK clock "L" width			0.4	—	0.6	tsucyc
tRISE	SSCK clock rising time	Master		—	—	1	tcyc <sup>(2)</sup>
		Slave		—	—	1	μs
tFALL	SSCK clock falling time	Master		—	—	1	tcyc <sup>(2)</sup>
		Slave		—	—	1	μs
tsu	SSO, SSI data input setup time			100	—	—	ns
tH	SSO, SSI data input hold time			1	—	—	tcyc <sup>(2)</sup>
tLEAD	$\overline{\text{SCS}}$ setup time	Slave		1tcyc + 50	—	—	ns
tLAG	$\overline{\text{SCS}}$ hold time	Slave		1tcyc + 50	—	—	ns
tOD	SSO, SSI data output delay time			—	—	1	tcyc <sup>(2)</sup>
tSA	SSI slave access time			—	—	1.5tcyc + 100	ns
tOR	SSI slave out open time			—	—	1.5tcyc + 100	ns

**NOTES:**

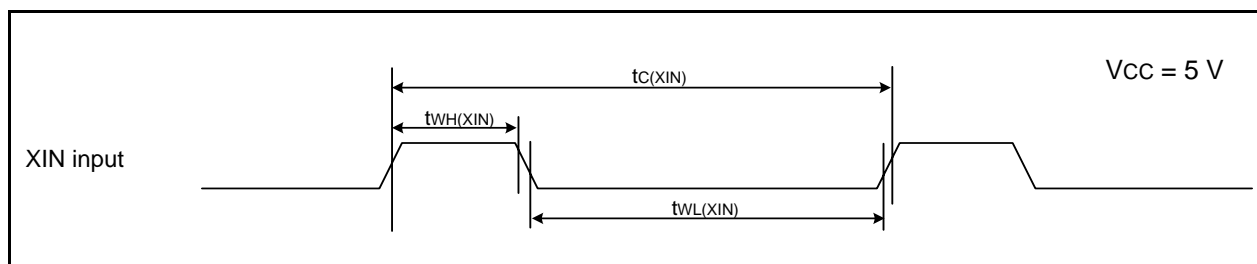
1.  $V_{CC} = 2.7$  to  $5.5$  V,  $V_{SS} = 0$  V at  $T_{opr} = -40$  to  $85^{\circ}\text{C}$  (J version) /  $-40$  to  $125^{\circ}\text{C}$  (K version), unless otherwise specified.
2.  $1\text{tcyc} = 1/f_1(\text{s})$



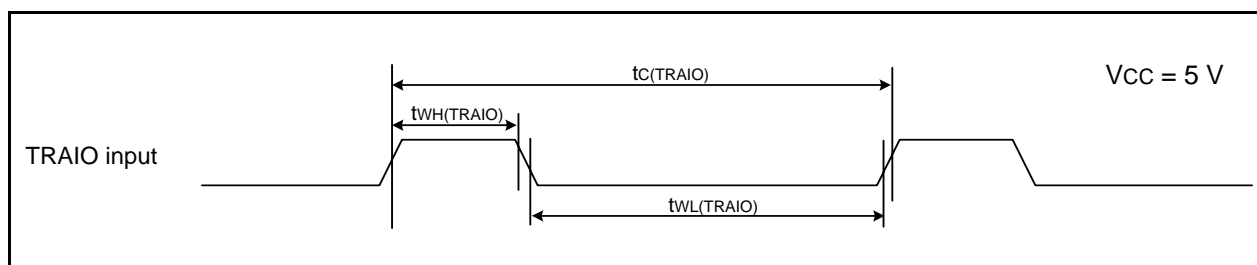
**Figure 5.25 I/O Timing of Clock Synchronous Serial I/O with Chip Select (Clock Synchronous Communication Mode)**

**Timing Requirements****(Unless Otherwise Specified:  $V_{CC} = 5\text{ V}$ ,  $V_{SS} = 0\text{ V}$  at  $T_{opr} = 25^{\circ}\text{C}$ ) [ $V_{CC} = 5\text{ V}$ ]****Table 5.49 XIN Input**

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(XIN)}$	XIN input cycle time	50	–	ns
$t_{WH(XIN)}$	XIN input "H" width	25	–	ns
$t_{WL(XIN)}$	XIN input "L" width	25	–	ns

**Figure 5.27 XIN Input Timing Diagram when  $V_{CC} = 5\text{ V}$** **Table 5.50 TRAIO Input**

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(TRAIO)}$	TRAIO input cycle time	100	–	ns
$t_{WH(TRAIO)}$	TRAIO input "H" width	40	–	ns
$t_{WL(TRAIO)}$	TRAIO input "L" width	40	–	ns

**Figure 5.28 TRAIO Input Timing Diagram when  $V_{CC} = 5\text{ V}$**

**Table 5.54 Electrical Characteristics (4) [V<sub>CC</sub> = 3 V]**  
**(T<sub>opr</sub> = -40 to 85°C (J version) / -40 to 125°C (K version), unless otherwise specified.)**

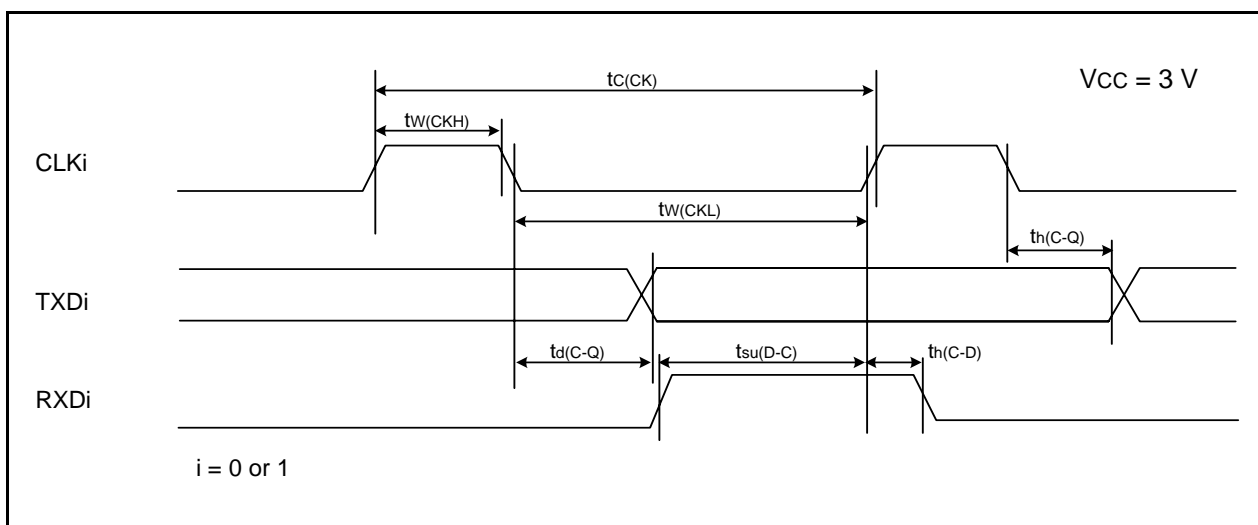
Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
I <sub>CC</sub>	Power supply current (V <sub>CC</sub> = 2.7 to 3.3 V) Single-chip mode, output pins are open, other pins are V <sub>SS</sub>	High-speed clock mode	—	6	—	mA
		High-speed on-chip oscillator mode	—	2	—	mA
		High-speed on-chip oscillator mode	—	5	9	mA
		Low-speed on-chip oscillator mode	—	2	—	mA
		Low-speed on-chip oscillator mode	—	130	300	μA
		Wait mode	—	25	70	μA
		Wait mode	—	23	55	μA
		Stop mode	—	0.7	3.0	μA
		Stop mode	—	1.1	—	μA
		Stop mode	—	3.8	—	μA



**Table 5.57 Serial Interface**

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(CK)}$	CLKi input cycle time	300	—	ns
$t_{w(CKH)}$	CLKi input "H" width	150	—	ns
$t_{w(CKL)}$	CLKi Input "L" width	150	—	ns
$t_{d(C-Q)}$	TXDi output delay time	—	80	ns
$t_{h(C-Q)}$	TXDi hold time	0	—	ns
$t_{su(D-C)}$	RXDi input setup time	70	—	ns
$t_{h(C-D)}$	RXDi input hold time	90	—	ns

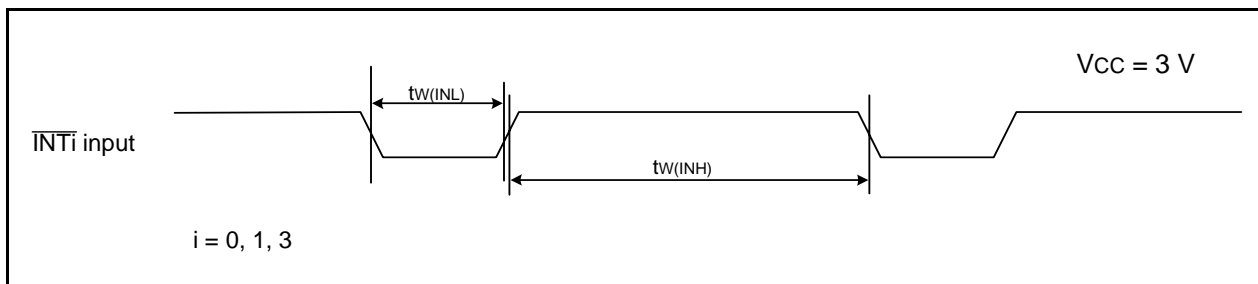
i = 0 or 1

**Figure 5.33 Serial Interface Timing Diagram when Vcc = 3 V****Table 5.58 External Interrupt  $\overline{INTi}$  (i = 0, 1, 3) Input**

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{w(INH)}$	$\overline{INTi}$ input "H" width	380 <sup>(1)</sup>	—	ns
$t_{w(INL)}$	$\overline{INTi}$ input "L" width	380 <sup>(2)</sup>	—	ns

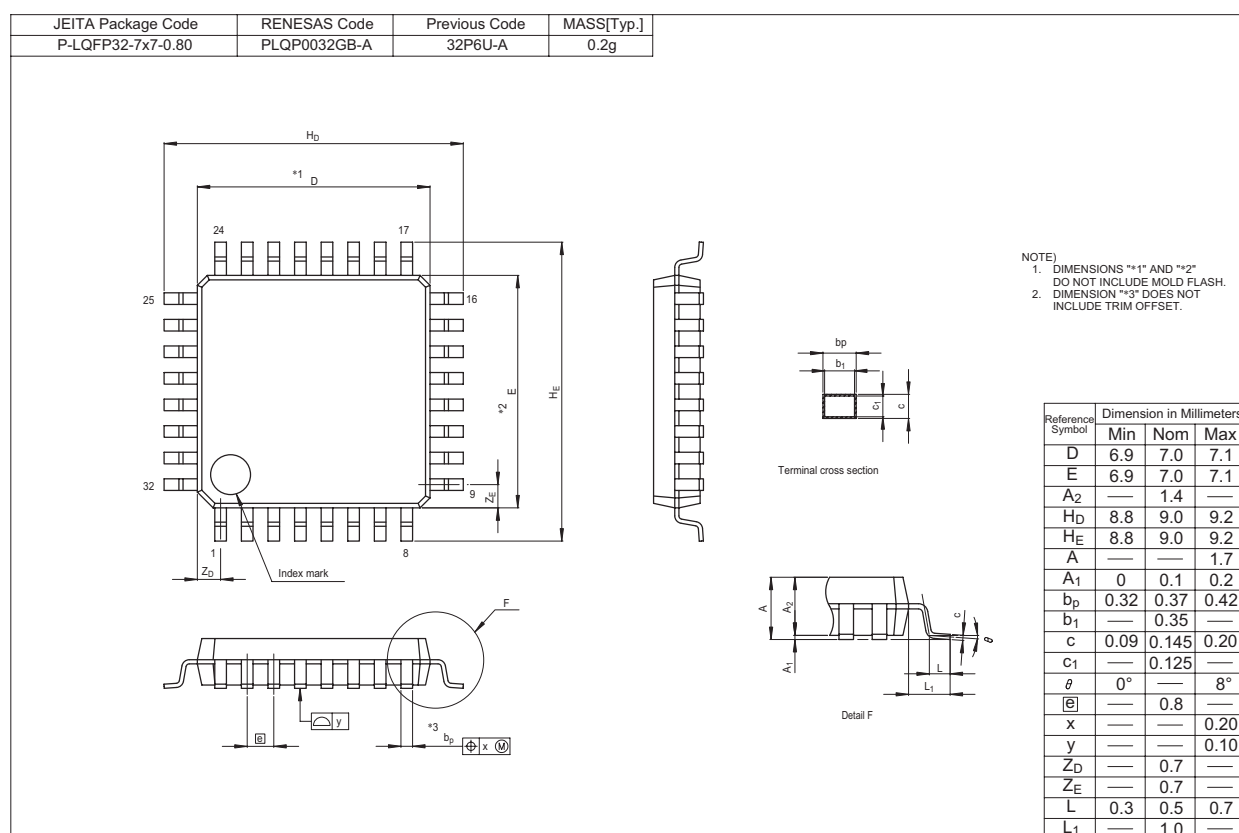
## NOTES:

1. When selecting the digital filter by the  $\overline{INTi}$  input filter select bit, use an  $\overline{INTi}$  input HIGH width of either (1/digital filter clock frequency × 3) or the minimum value of standard, whichever is greater.
2. When selecting the digital filter by the  $\overline{INTi}$  input filter select bit, use an  $\overline{INTi}$  input LOW width of either (1/digital filter clock frequency × 3) or the minimum value of standard, whichever is greater.

**Figure 5.34 External Interrupt  $\overline{INTi}$  Input Timing Diagram when Vcc = 3 V**

## Package Dimensions

Diagrams showing the latest package dimensions and mounting information are available in the “Packages” section of the Renesas Technology website.



REVISION HISTORY	R8C/26 Group, R8C/27 Group Datasheet
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Rev.	Date	Description	
		Page	Summary
0.10	Nov 14, 2005	–	First edition issued
0.20	Feb 06, 2006	2, 3	Table 1.1 Functions and Specifications for R8C/26Group and Table 1.2 Functions and Specifications for R8C/27 Group; Minimum instruction execution time and Supply voltage revised
		9	Table 1.6 Pin Name Information by Pin Number; “XOUT” → “XOUT/XCOUT” and “XIN” → “XIN/XCIN” revised
		18	Table 4.4 SFR Information (4); 00FEh: “DRR” → “P1DRR” revised
		19	Table 4.5 SFR Information (5); -0119h: “Timer RE Minute Data Register / Compare Register” → “Timer RE Minute Data Register / Compare Data Register” -011Ah: “Timer RE Time Data Register” → “Timer RE Hour Data Register” -011Bh: “Timer RE Day Data Register” → “Timer RE Day of Week Data Register” revised
		22 to 45	5. Electrical Characteristics added
1.00	Nov 08, 2006	All pages	“Preliminary” deleted
		2	Table 1.1 revised
		3	Table 1.2 revised
		4	Figure 1.1 revised
		5	Table 1.3 revised
		6	Table 1.4 revised
		7	Figure 1.4 revised
		9	Table 1.6 revised
		15	Table 4.1; • 001Ch: “00h” → “00h, 10000000b” revised • 000Fh: “000XXXXXb” → “00X11111b” revised • 0029h: “High-Speed On-Chip Oscillator Control Register 4, FRA4, When shipping” added • 002Bh: “High-Speed On-Chip Oscillator Control Register 6, FRA6, When shipping” added • 0032h: “00h, 01000000b” → “00h, 00100000b” revised • 0038h: “00001000b, 01001001b” → “0000X000b, 0100X001b” revised • NOTE3 and 4 revised; NOTE6 added
		18	Table 4.4; • 00E0h, 00E1h, 00E5h, 00E8h, 00E9h: “XXh” → “00h” revised • 00FDh: “XX00000000b” → “00h” revised
		22	Table 5.2 revised
		23	Figure 5.1 title revised
		24	Table 5.4 revised
		25	Table 5.5 revised
		26	Figure 5.2 title revised and Table 5.7 NOTE4 added

# REVISION HISTORY

# R8C/26 Group, R8C/27 Group Datasheet

Rev.	Date	Description	
		Page	Summary
1.00	Nov 08, 2006	27	Table 5.9, Figure 5.3 revised and Table 5.10 deleted
		28	Table 5.10, Table 5.11 revised
		34	Table 5.15 revised
		35	Table 5.16 revised
		36	Table 5.17 revised
		39	Table 5.22 revised
		40	Table 5.23 revised
		44	Table 5.29 revised
		47	Package Dimensions; "Diagrams showing the latest...website." added
1.10	Nov 29, 2006	All pages	"J, K version" added
		1	1 "J and K versions are under development...notice." added 1.1 revised
		2	Table 1.1 revised
		3	Table 1.2 revised
		4	Figure 1.1 NOTE3 added
		5	Table 1.3, Figure 1.2 revised
		6	Table 1.4, Figure 1.3 revised
		7	Figure 1.4 NOTE3 added
		8	Table 1.5 revised
		9	Table 1.6 NOTE2 added
		13	Figure 3.1 revised
		14	Figure 3.2 revised
		15	Table 4.1; "0000h to 003Fh" → "0000h to 002Fh" revised • NOTE3 added
		16	Table 4.2; "0040h to 007Fh" → "0030h to 007Fh" revised • 0032h, 0036h: "After reset" is revised • 0038h: NOTE revised • NOTES 2, 5, 6 revised and NOTE 7, 8 added
		19	Table 4.5 NOTE2 added
		28	Table 5.10 revised
		48 to 66	5.2 J, K Version added
1.20	Jan 17, 2007	18	Table 4.4 NOTE2 added
1.30	May 25, 2007	2	Table 1.1 revised
		3	Table 1.2 revised
		5	Table 1.3 revised
		6	Figure 1.2 revised
		7	Table 1.4 revised
		8	Figure 1.3 revised
		9	Figure 1.4 NOTE4 added
		15	Figure 3.1 part number revised

Notes:

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**Renesas Technology Malaysia Sdn. Bhd**  
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